

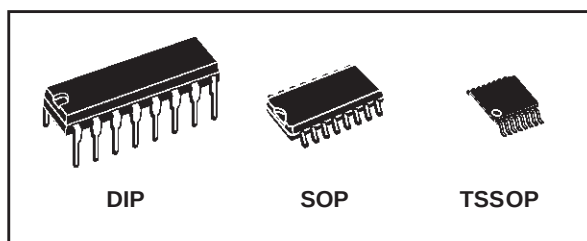
SYNCHRONOUS PRESETTABLE 4-BIT COUNTER

- HIGH SPEED:
 $f_{MAX} = 200\text{MHz}$ (TYP.) at $V_{CC} = 5\text{V}$
- LOW POWER DISSIPATION:
 $I_{CC} = 8\mu\text{A}$ (MAX.) at $T_A = 25^\circ\text{C}$
- HIGH NOISE IMMUNITY:
 $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (MIN.)
- 50Ω TRANSMISSION LINE DRIVING CAPABILITY
- SYMMETRICAL OUTPUT IMPEDANCE:
 $|I_{OH}| = I_{OL} = 24\text{mA}$ (MIN)
- BALANCED PROPAGATION DELAYS:
 $t_{PLH} \equiv t_{PHL}$
- OPERATING VOLTAGE RANGE:
 V_{CC} (OPR) = 2V to 6V
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 163
- IMPROVED LATCH-UP IMMUNITY

DESCRIPTION

The 74AC163 is an advanced high-speed CMOS SYNCHRONOUS PRESETTABLE COUNTER fabricated with sub-micron silicon gate and double-layer metal wiring C²MOS technology. It is a 4 bit binary counter with Synchronous Clear.

The circuit have four fundamental modes of operation, in order of preference: synchronous reset, parallel load, count-up and hold. Four control inputs, Master Reset (CLEAR), Parallel Enable Input (LOAD), Count Enable Input (PE) and Count Enable Carry Input (TE), determine the

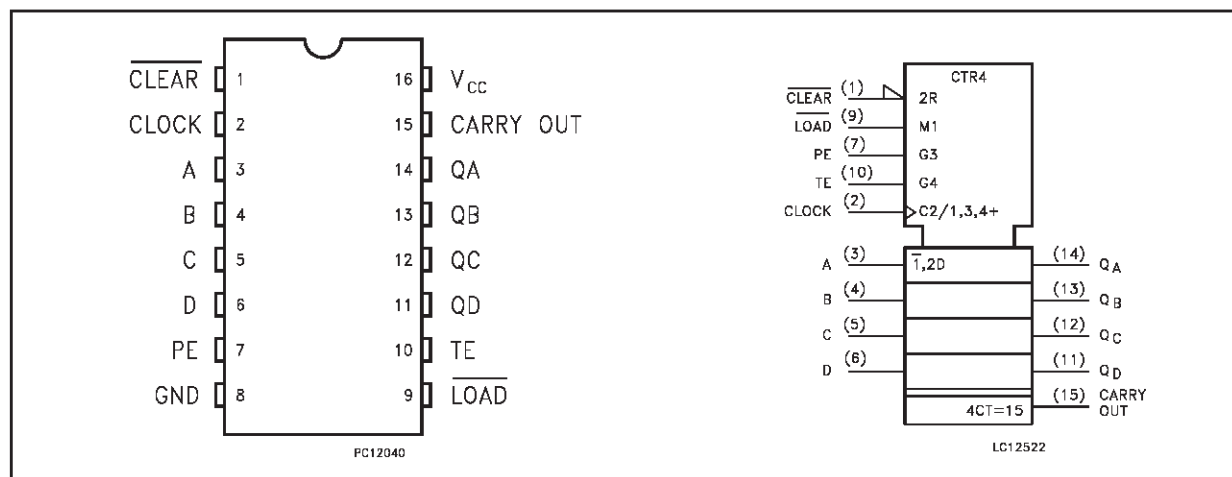


ORDER CODES

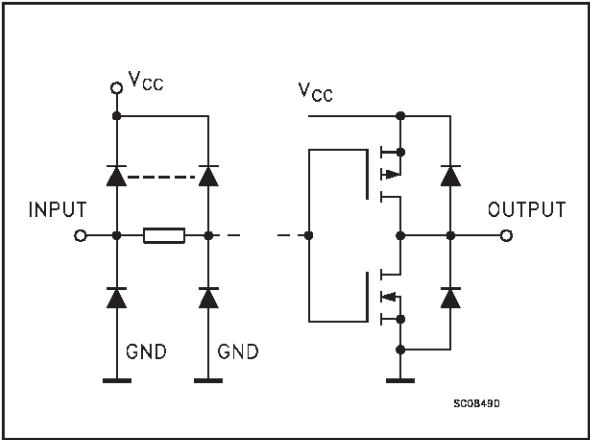
PACKAGE	TUBE	T & R
DIP	74AC163B	
SOP	74AC163M	74AC163MTR
TSSOP		74AC163TTR

mode of operation as shown in the Truth Table. A LOW signal on CLEAR overrides counting and parallel loading and sets all outputs on LOW state on the next rising edge of CLOCK. A LOW signal on LOAD overrides counting and allows information on Parallel Data inputs to be loaded into the flip-flop on the next rising edge of CLOCK. With LOAD and CLEAR HIGH, PE and TE permit counting when both are HIGH. Conversely, a LOW signal on either PE and TE inhibits counting. All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

PIN CONNECTION AND IEC LOGIC SYMBOLS



INPUT AND OUTPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

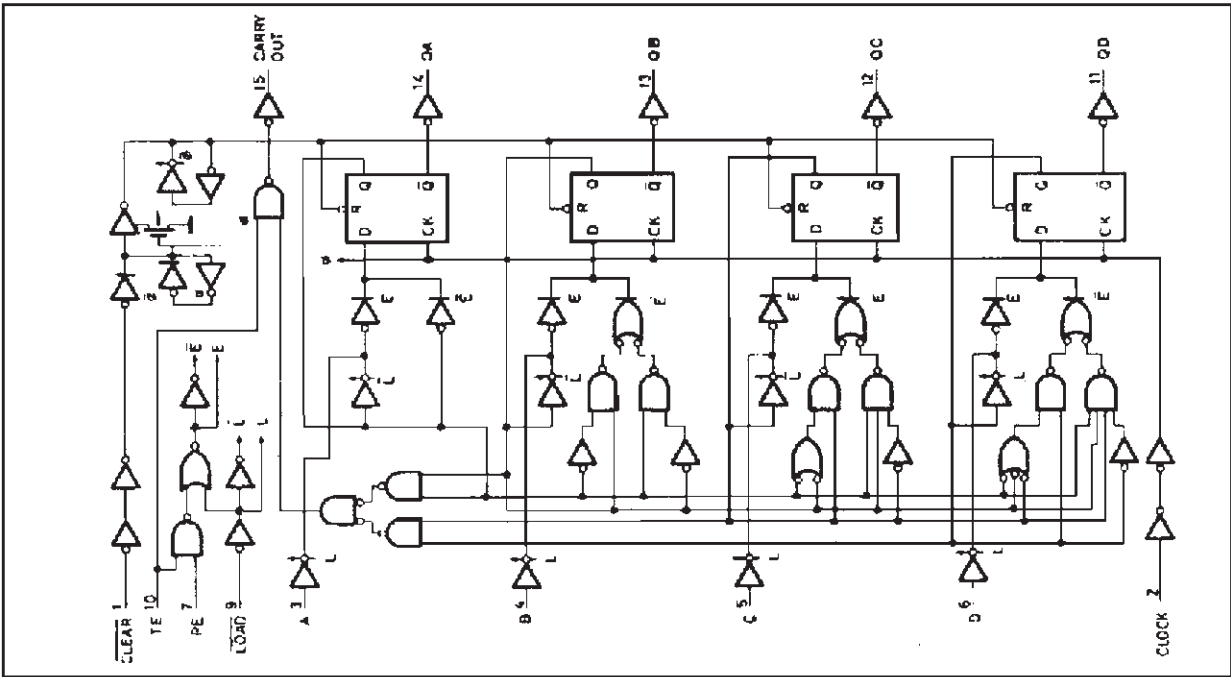
PIN No	SYMBOL	NAME AND FUNCTION
1	CLEAR	Master Reset
2	CLOCK	Clock Input (LOW to HIGH Edge Trigger)
3, 4, 5, 6	A, B, C, D	Data Inputs
7	PE	Count Enable Input
10	TE	Count Enable Carry Input
9	LOAD	Parallel Enable Input
14, 13, 12, 11	QA to QD	Flip-Flop Outputs
15	CARRY OUT	Terminal Count Output
8	GND	Ground (0V)
16	VCC	Positive Supply Voltage

TRUTH TABLE

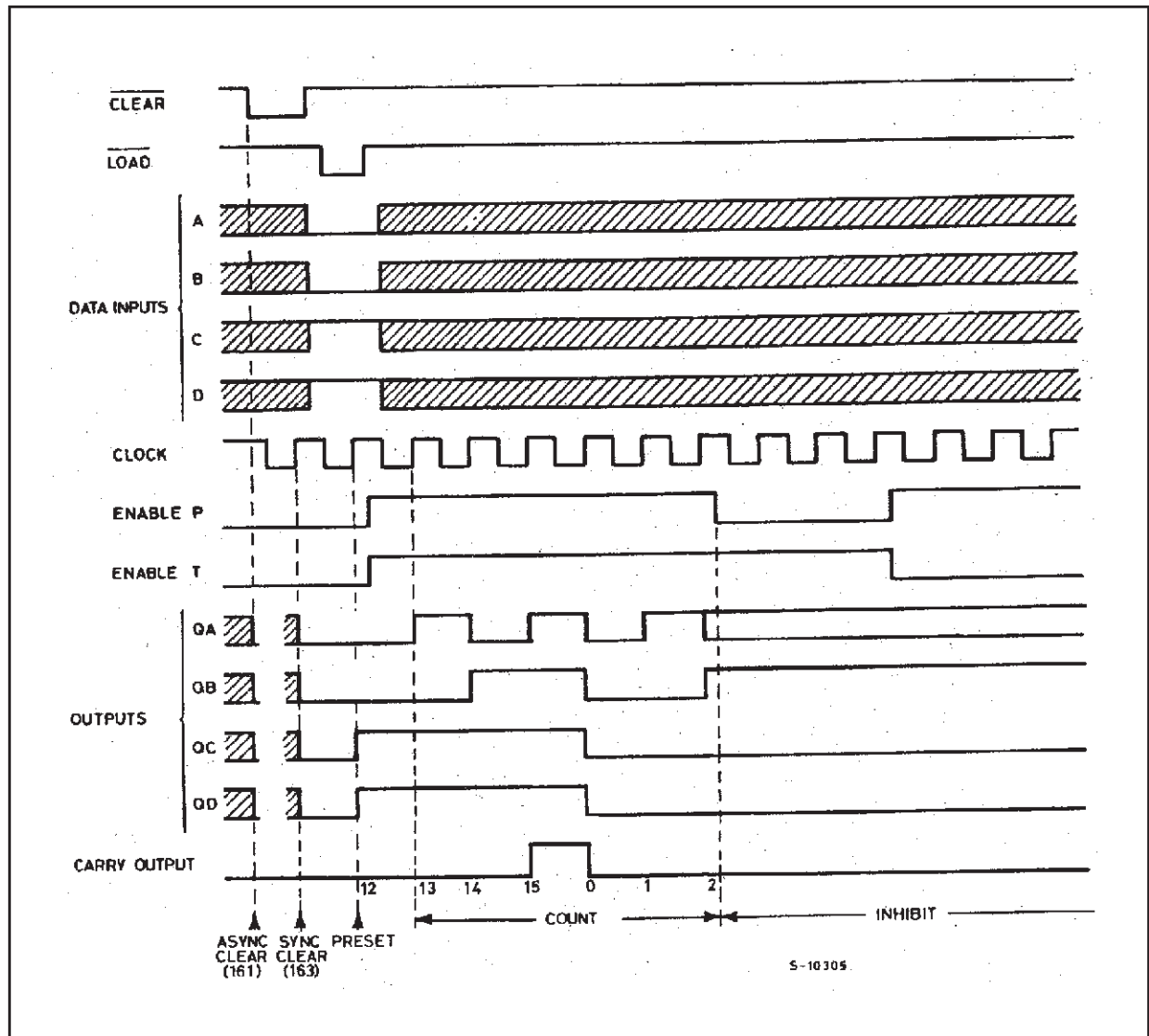
INPUTS					OUTPUTS				FUNCTION
CLEAR	LOAD	PE	TE	CK					
L	X	X	X		L	L	L	L	RESET TO "0"
H	L	X	X		A	B	C	D	PRESET DATA
H	H	X	L		NO CHANGE				NO COUNT
H	H	L	X		NO CHANGE				NO COUNT
H	H	H	H		COUNT UP				COUNT
H	X	X	X		NO CHANGE				NO COUNT

X : Don't Care; A, B, C, D; Logic level of data input; CARRY OUT : TE x QA x QB x QC x QD

LOGIC DIAGRAM



TIMING CHART



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7	V
V_I	DC Input Voltage	-0.5 to $V_{CC} + 0.5$	V
V_O	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
I_{IK}	DC Input Diode Current	± 20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 50	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 300	mA
T_{stg}	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	2 to 6	V
V_I	Input Voltage	0 to V_{CC}	V
V_O	Output Voltage	0 to V_{CC}	V
T_{op}	Operating Temperature	-55 to 125	°C
dt/dv	Input Rise and Fall Time $V_{CC} = 3.0, 4.5$ or $5.5V$ (note 1)	8	ns/V

1) V_{IN} from 30% to 70% of V_{CC}

DC SPECIFICATIONS

Symbol	Parameter	Test Condition		Value							Unit
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V _{IH}	High Level Input Voltage	3.0	V _O = 0.1 V or V _{CC} -0.1V	2.1	1.5		2.1		2.1		V
		4.5		3.15	2.25		3.15		3.15		
		5.5		3.85	2.75		3.85		3.85		
V _{IL}	Low Level Input Voltage	3.0	V _O = 0.1 V or V _{CC} -0.1V		1.5	0.9		0.9		0.9	V
		4.5			2.25	1.35		1.35		1.35	
		5.5			2.75	1.65		1.65		1.65	
V _{OH}	High Level Output Voltage	3.0	I _O =-50 μA	2.9	2.99		2.9		2.9		V
		4.5	I _O =-50 μA	4.4	4.49		4.4		4.4		
		5.5	I _O =-50 μA	5.4	5.49		5.4		5.4		
		3.0	I _O =-12 mA	2.56			2.46		2.4		
		4.5	I _O =-24 mA	3.86			3.76		3.7		
		5.5	I _O =-24 mA	4.86			4.76		4.7		
V _{OL}	Low Level Output Voltage	3.0	I _O =50 μA		0.002	0.1		0.1		0.1	V
		4.5	I _O =50 μA		0.001	0.1		0.1		0.1	
		5.5	I _O =50 μA		0.001	0.1		0.1		0.1	
		3.0	I _O =12 mA			0.36		0.44		0.5	
		4.5	I _O =24 mA			0.36		0.44		0.5	
		5.5	I _O =24 mA			0.36		0.44		0.5	
I _I	Input Leakage Current	5.5	V _I = V _{CC} or GND			± 0.1		± 1		± 1	μA
I _{CC}	Quiescent Supply Current	5.5	V _I = V _{CC} or GND			8		80		160	μA
I _{OLD}	Dynamic Output Current (note 1, 2)	5.5	V _{OLD} = 1.65 V max					75		50	mA
I _{OHD}			V _{OHD} = 3.85 V min					-75		-50	mA

1) Maximum test duration 2ms, one output loaded at time

2) Incident wave switching is guaranteed on transmission lines with impedances as low as 50Ω

AC ELECTRICAL CHARACTERISTICS ($C_L = 50 \text{ pF}$, $R_L = 500 \Omega$, Input $t_r = t_f = 3 \text{ ns}$)

Symbol	Parameter	Test Condition		Value						Unit	
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.		Max.
t _{PLH} t _{PHL}	Propagation Delay Time CLOCK to Q	3.3 ^(*)			7.0	12.0		13.0		13.0	ns
		5.0 ^(**)			5.0	9.0		9.5		9.5	
t _{PLH} t _{PHL}	Propagation Delay Time CLOCK to CARRY OUT	3.3 ^(*)			8.0	14.0		15.0		15.0	ns
		5.0 ^(**)			6.0	10.5		11.5		11.5	
t _{PLH} t _{PHL}	Propagation Delay Time TE to CARRY OUT	3.3 ^(*)			5.5	9.5		11.0		11.0	ns
		5.0 ^(**)			4.0	6.5		7.5		7.5	
t _W	CK pulse Width, (Count) HIGH or LOW	3.3 ^(*)			2.0	4.5		7.5		7.5	ns
		5.0 ^(**)			2.0	4.0		4.5		4.5	
t _W	CK pulse Width, (Load) HIGH or LOW	3.3 ^(*)			2.0	3.0		3.5		3.5	ns
		5.0 ^(**)			2.0	2.5		3.0		3.0	
t _s	Setup Time HIGH or LOW (INPUT to CLOCK)	3.3 ^(*)			2.0	4.0		5.0		5.0	ns
		5.0 ^(**)			1.5	3.0		4.0		4.0	
t _n	Hold Time HIGH or LOW (INPUT to CLOCK)	3.3 ^(*)			-1.5	-0.5		0		0	ns
		5.0 ^(**)			-1.0	0.5		1.0		1.0	
t _s	Setup Time <u>HIGH</u> or LOW (CLEAR to CLOCK)	3.3 ^(*)			1.0	3.0		4.0		4.0	ns
		5.0 ^(**)			1.0	3.5		4.5		4.5	
t _h	Hold Time <u>HIGH</u> or LOW (CLEAR to CLOCK)	3.3 ^(*)			-0.5	0.5		1.0		1.0	ns
		5.0 ^(**)			-0.3	0.5		1.0		1.0	
t _s	Setup Time <u>HIGH</u> or LOW (LOAD to CLOCK)	3.3 ^(*)			3.0	5.0		8.0		8.0	ns
		5.0 ^(**)			2.5	6.0		7.0		7.0	
t _h	Hold Time <u>HIGH</u> or LOW (LOAD to CLOCK)	3.3 ^(*)			-2.5	-1.0		-0.5		-0.5	ns
		5.0 ^(**)			-1.5	0		0.5		0.5	
t _s	Setup Time HIGH or LOW (PE or TE to CLOCK)	3.3 ^(*)			3.0	6.0		7.0		7.0	ns
		5.0 ^(**)			2.0	4.0		5.0		5.0	
t _h	Hold Time HIGH or LOW (PE or TE to CLOCK)	3.3 ^(*)			-2.0	-0.5		0		0	ns
		5.0 ^(**)			-1.5	0		0.5		0.5	
f _{MAX}	Maximum Clock Frequency	3.3 ^(*)		70	200		60		60		MHz
		5.0 ^(**)		110	200		95		95		

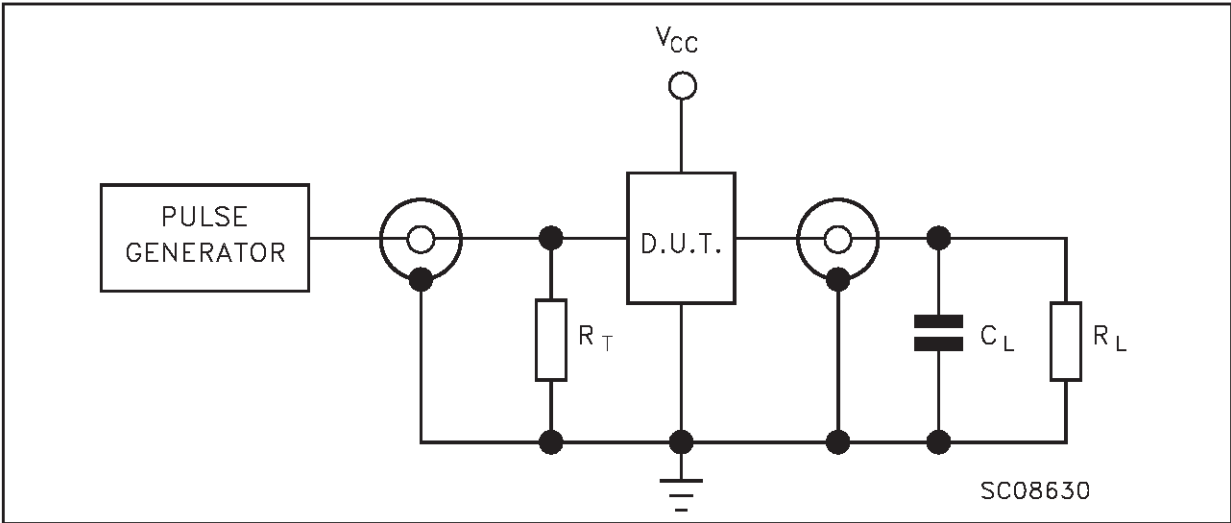
(*) Voltage range is $3.3\text{V} \pm 0.3\text{V}$ (**) Voltage range is $5.0\text{V} \pm 0.5\text{V}$

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Condition		Value								Unit
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C			
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.		
C _{IN}	Input Capacitance	5.0			4.5						pF	
C _{PD}	Power Dissipation Capacitance (note1)	5.0	f _{IN} = 10MHz		37						pF	

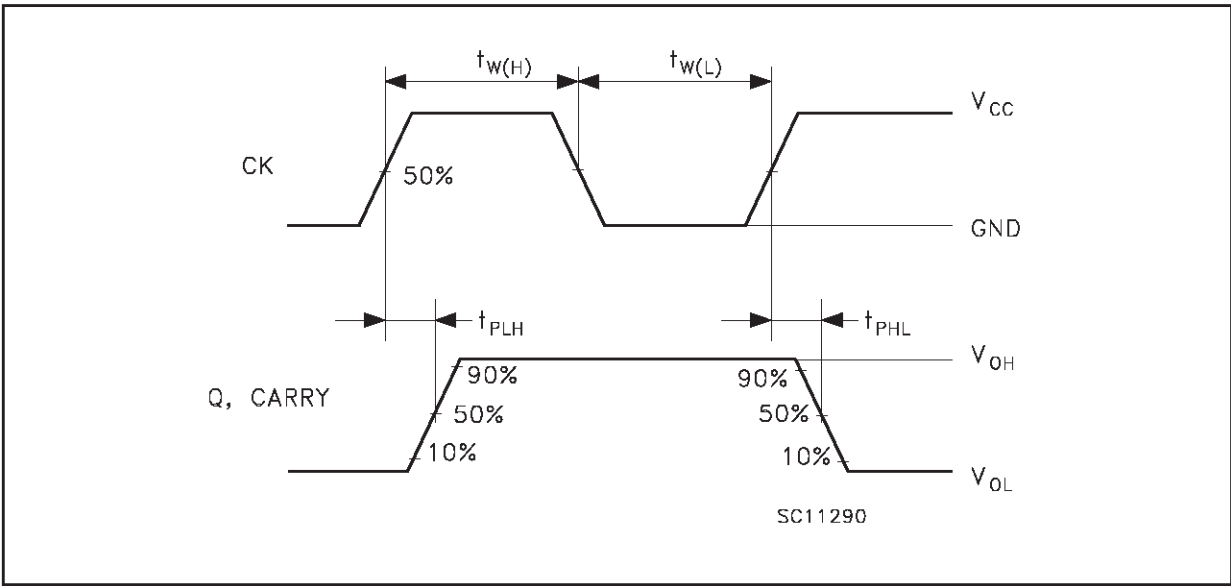
1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. I_{CC(opr)} = C_{PD} × V_{CC} × f_{IN} + I_{CC}/n (per circuit)

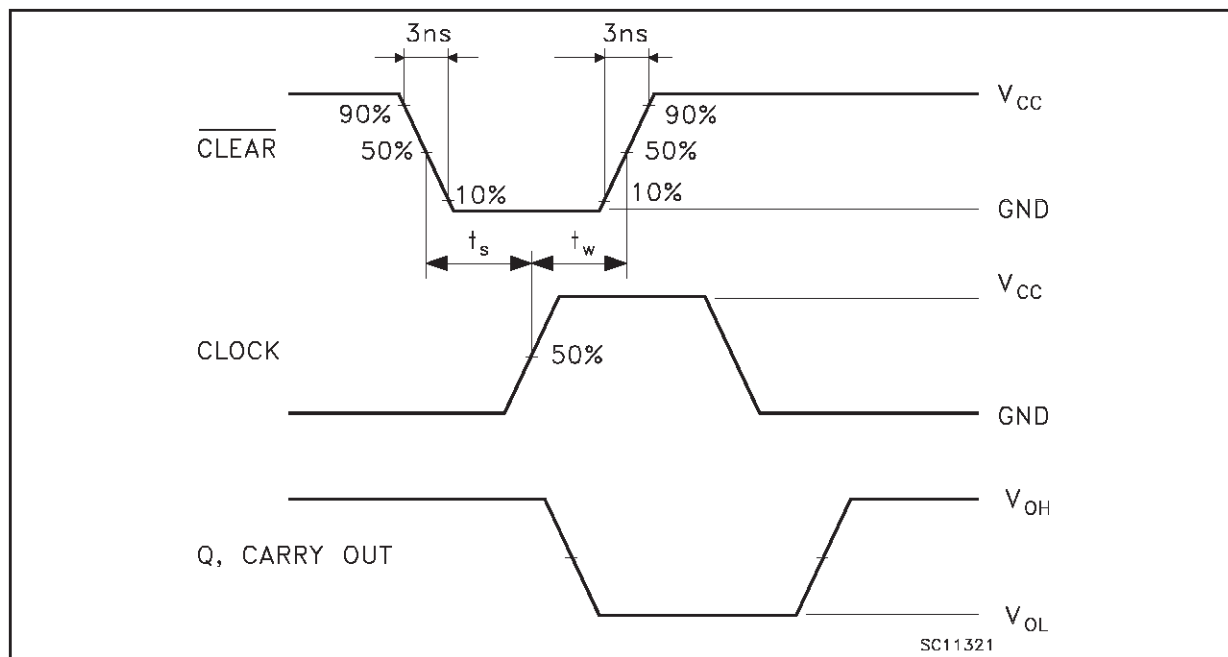
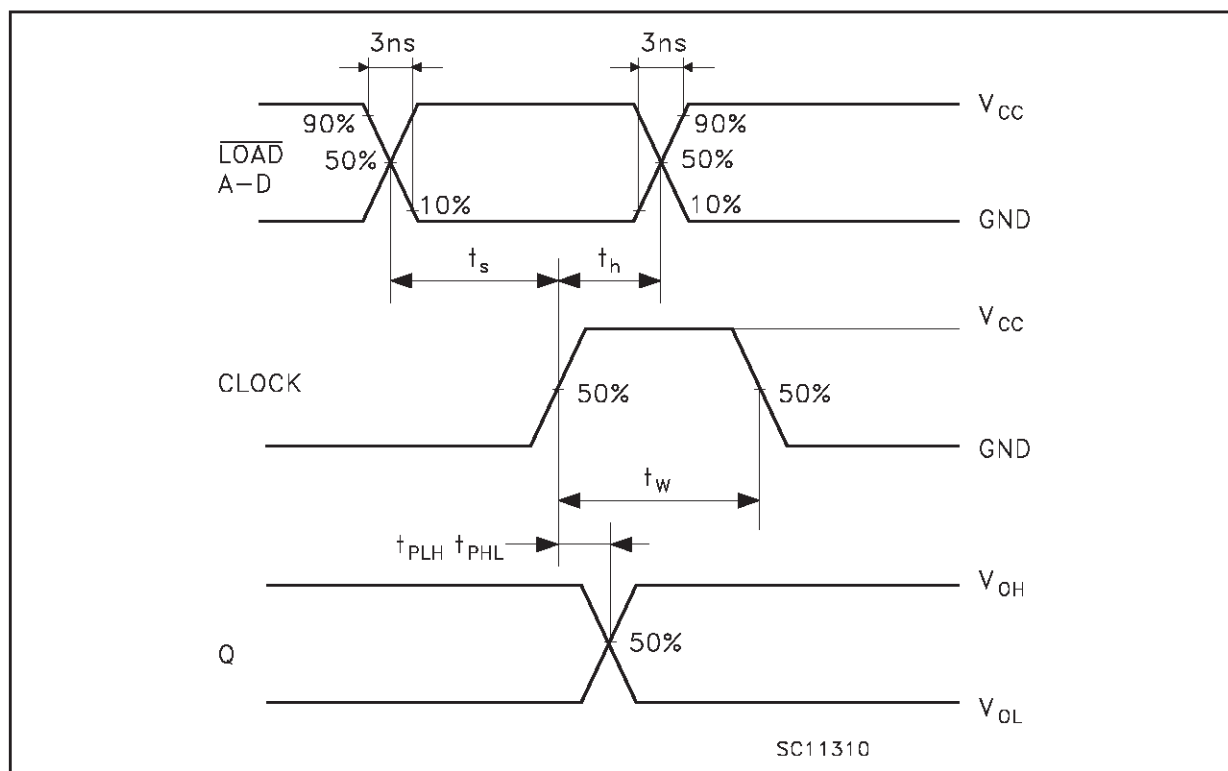
TEST CIRCUIT

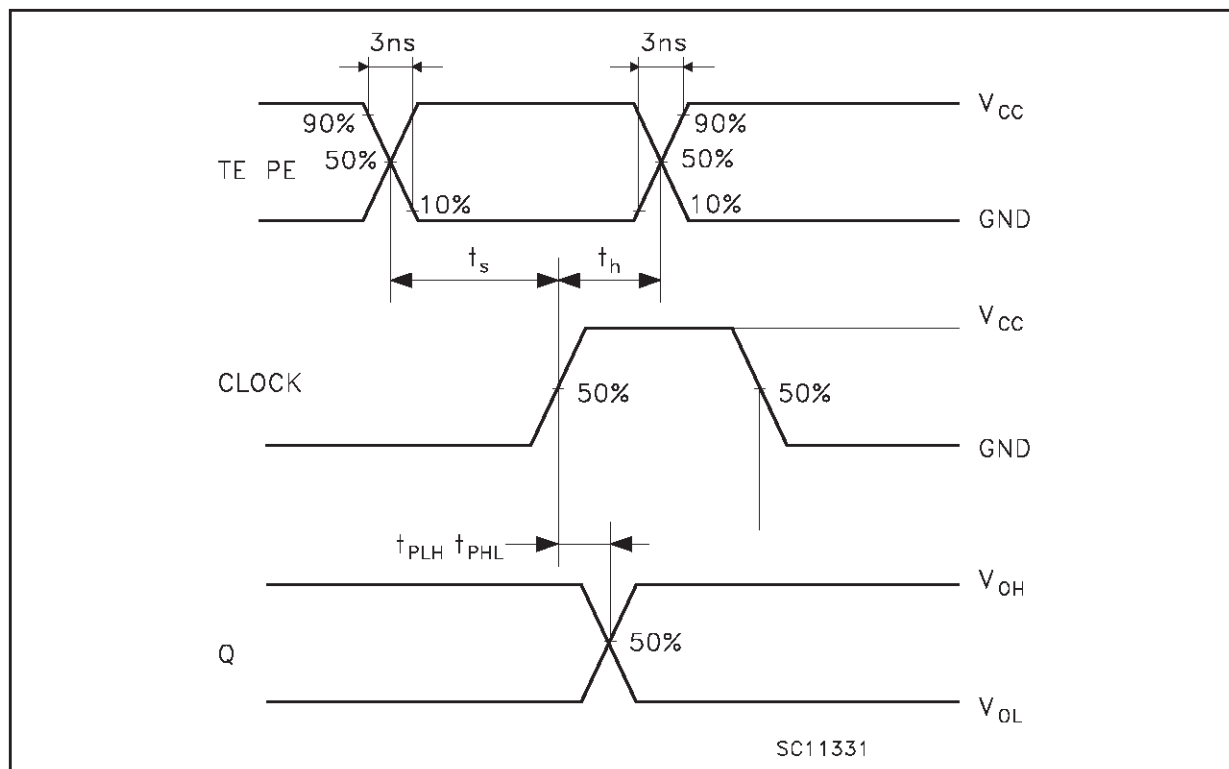
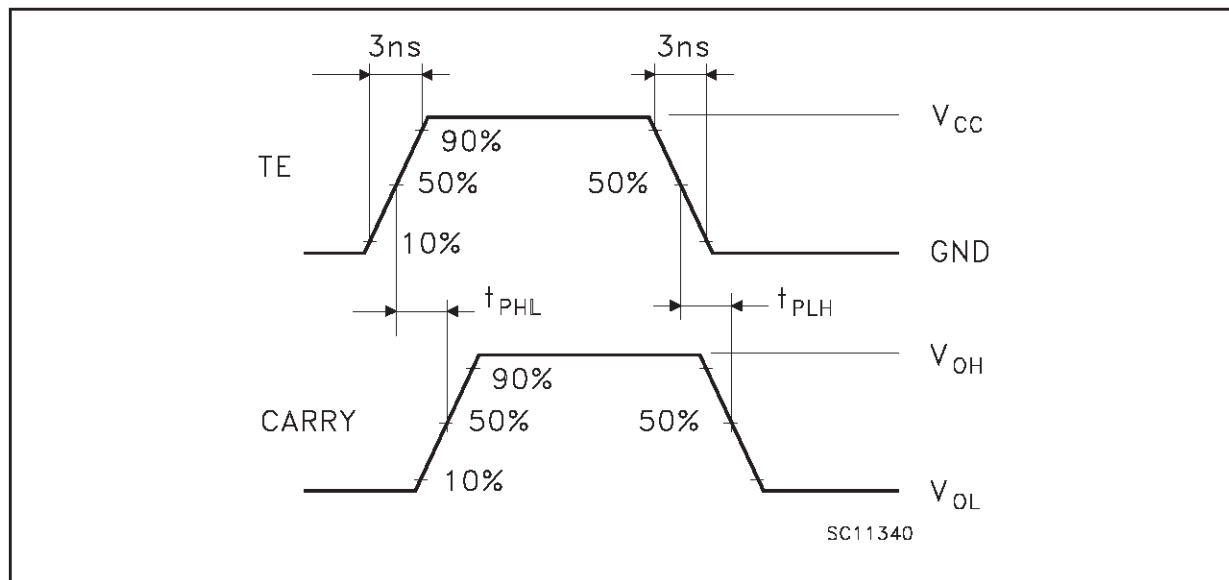


C_L = 50pF or equivalent (includes jig and probe capacitance)
R_L = R_T = 500Ω or equivalent
R_T = Z_{OUT} of pulse generator (typically 50Ω)

WAVEFORM 1: PROPAGATION DELAYS, COUNT MODE (f=1MHz; 50% duty cycle)

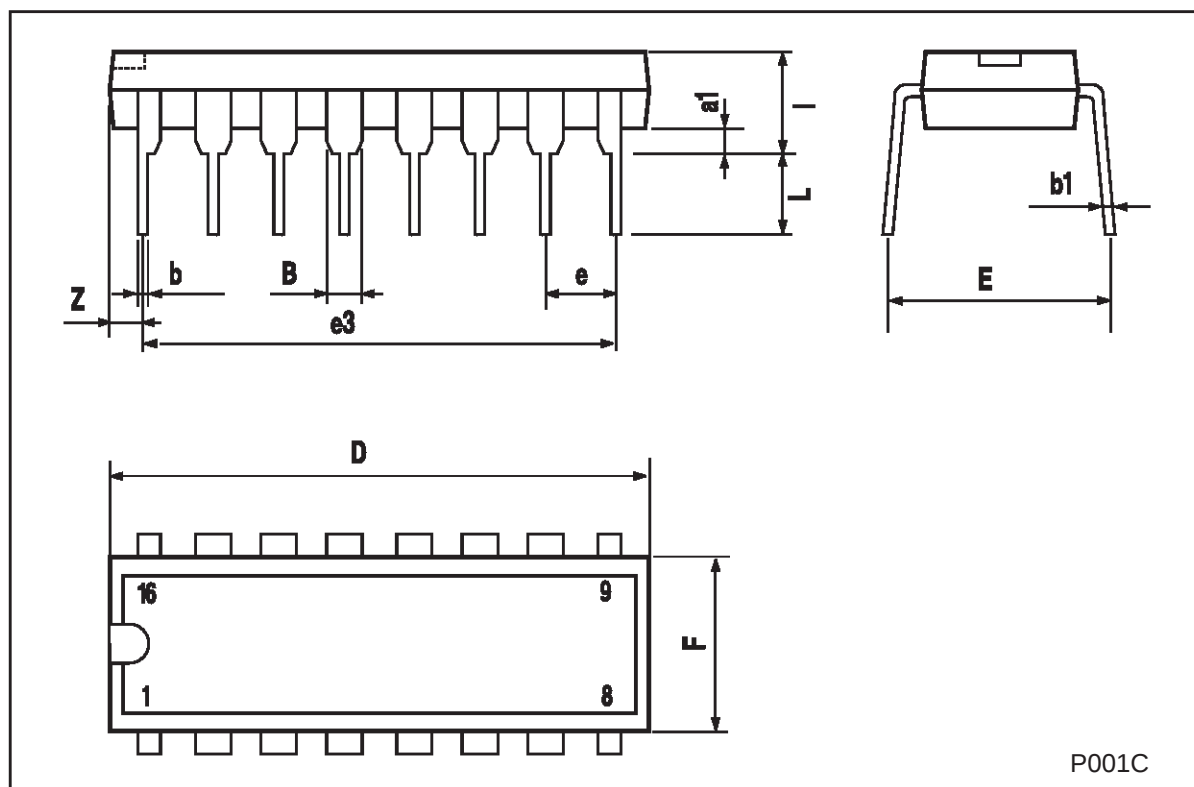


WAVEFORM 2: PROPAGATION DELAYS CLEAR MODE ($f=1\text{MHz}$; 50% duty cycle)**WAVEFORM 3: PROPAGATION DELAYS PRESET MODE** ($f=1\text{MHz}$; 50% duty cycle)

WAVEFORM 4: PROPAGATION DELAYS COUNTABLE MODE ($f=1\text{MHz}$; 50% duty cycle)**WAVEFORM 5: PROPAGATION DELAYS CASCADE MODE** ($f=1\text{MHz}$; 50% duty cycle)

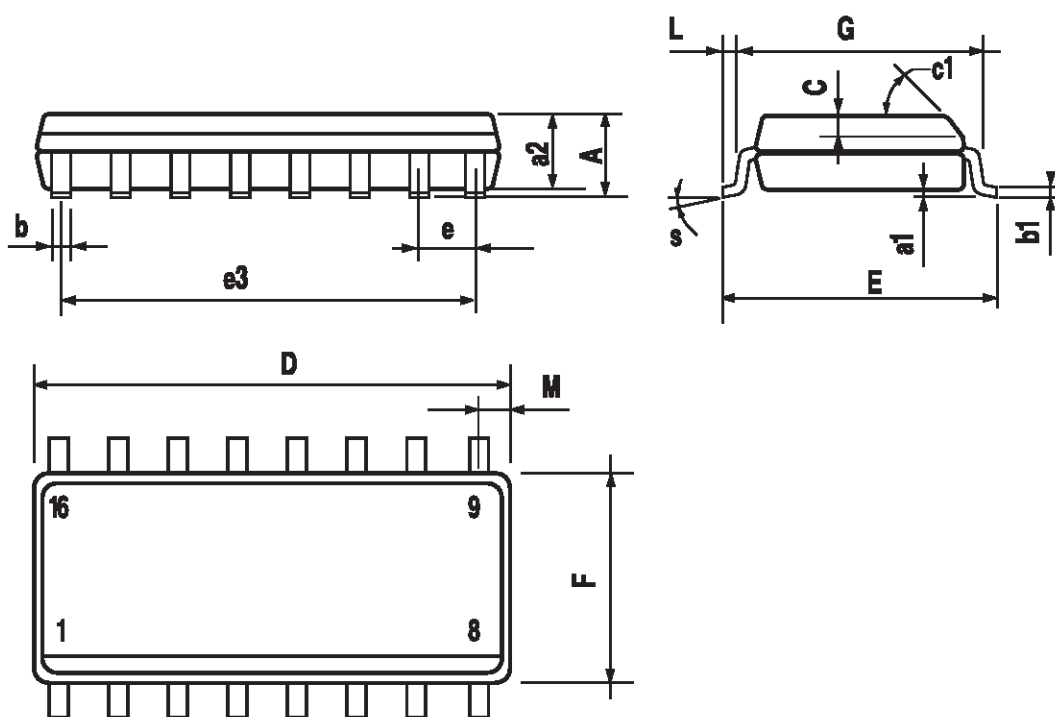
Plastic DIP-16 (0.25) MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
a1	0.51			0.020		
B	0.77		1.65	0.030		0.065
b		0.5			0.020	
b1		0.25			0.010	
D			20			0.787
E		8.5			0.335	
e		2.54			0.100	
e3		17.78			0.700	
F			7.1			0.280
I			5.1			0.201
L		3.3			0.130	
Z			1.27			0.050



SO-16 MECHANICAL DATA

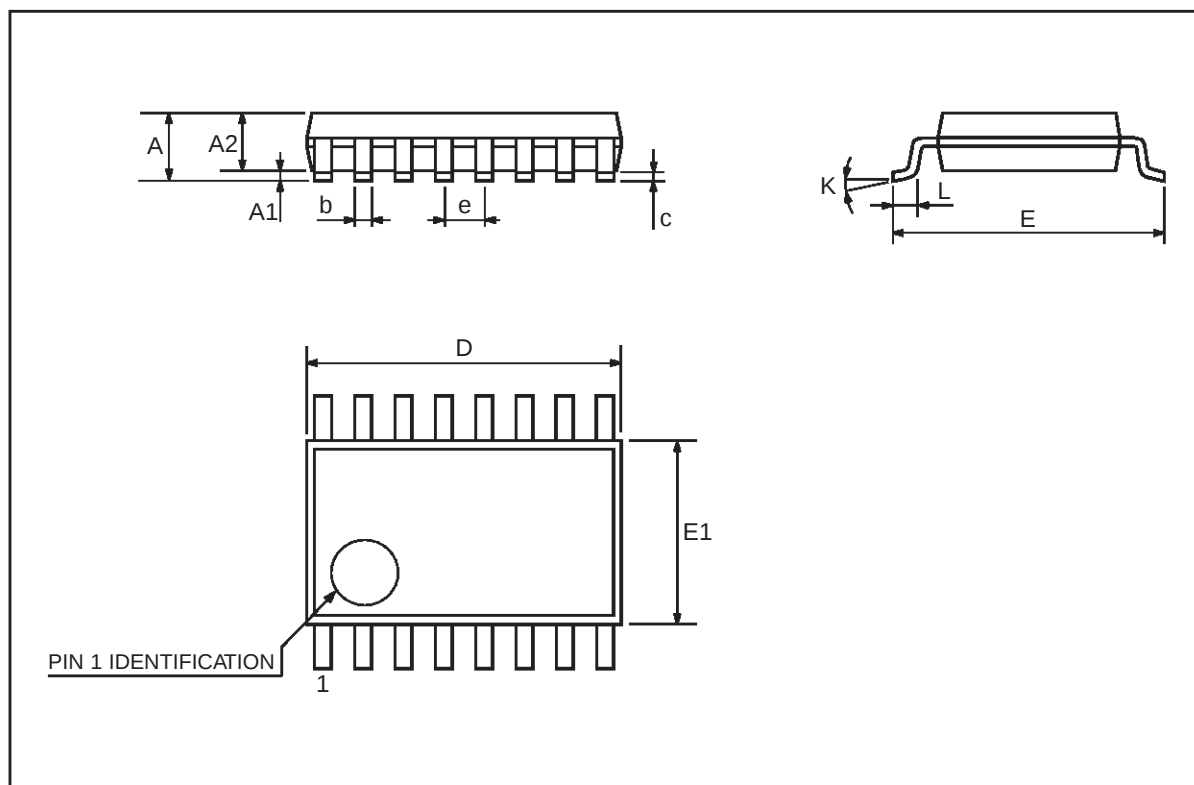
DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.2	0.004		0.007
a2			1.65			0.064
b	0.35		0.46	0.013		0.018
b1	0.19		0.25	0.007		0.010
C		0.5			0.019	
c1	45 (typ.)					
D	9.8		10	0.385		0.393
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		8.89			0.350	
F	3.8		4.0	0.149		0.157
G	4.6		5.3	0.181		0.208
L	0.5		1.27	0.019		0.050
M			0.62			0.024
S	8 (max.)					



P013H

TSSOP16 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.1			0.433
A1	0.05	0.10	0.15	0.002	0.004	0.006
A2	0.85	0.9	0.95	0.335	0.354	0.374
b	0.19		0.30	0.0075		0.0118
c	0.09		0.20	0.0035		0.0079
D	4.9	5	5.1	0.193	0.197	0.201
E	6.25	6.4	6.5	0.246	0.252	0.256
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°	4°	8°	0°	4°	8°
L	0.50	0.60	0.70	0.020	0.024	0.028



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